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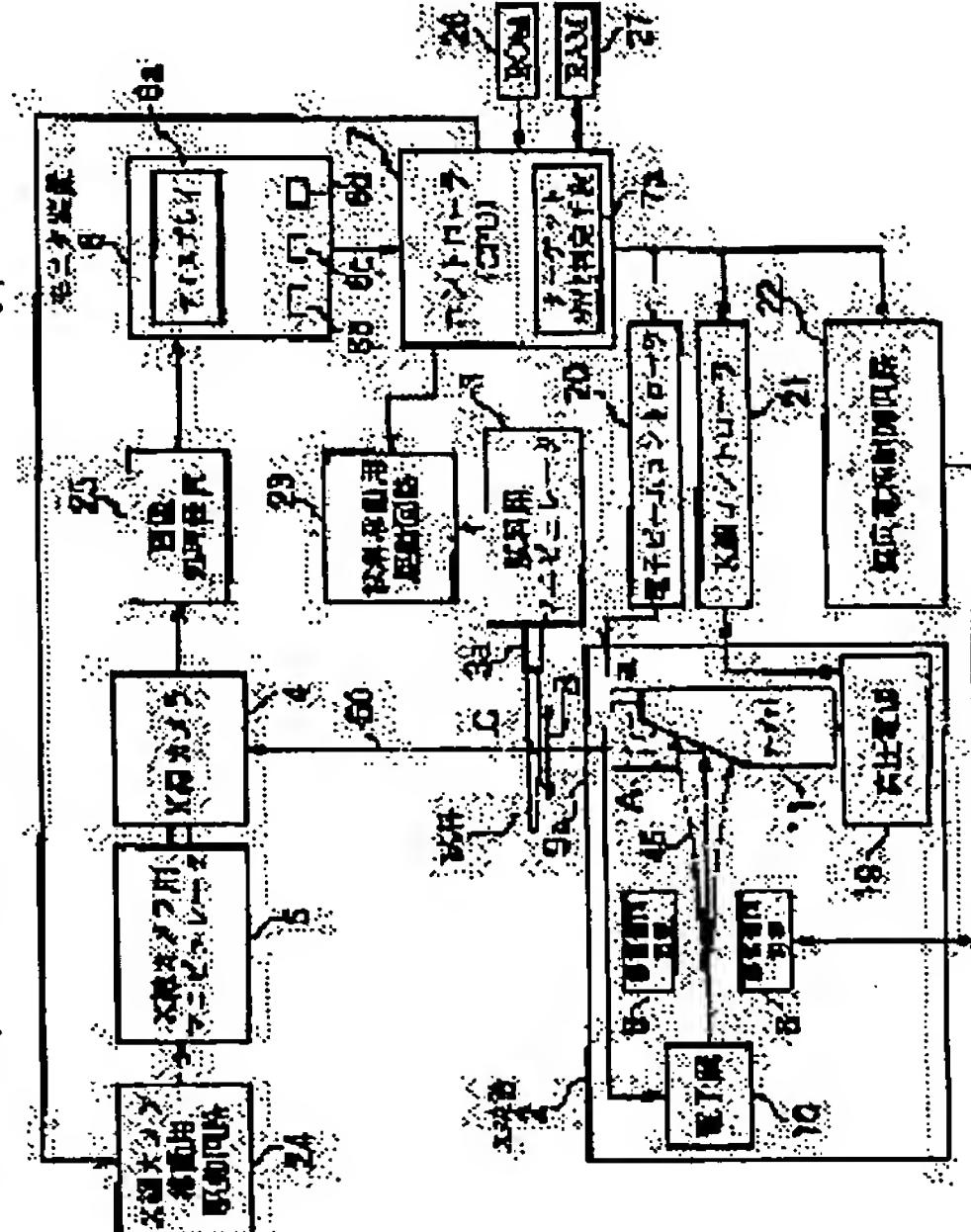
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## (54) X-RAY INSPECTING DEVICE

### (57)Abstract:

**PROBLEM TO BE SOLVED:** To scale the image of a sample by a new constitution.

**SOLUTION:** An electronic beam deflecting means 8 is controlled by a controller 7 to deflect electrons 45 heading for a target 11 in the first directions A coming close to and apart from an X-ray emergent window 9a by the electron beam deflecting means 8 and to move the location of collision of the electrons 45 against the target 11 in the first directions A. Then by changing the path length of X rays between the location of collision and a sample 1 and an X-ray image pickup device 4, it becomes possible to obtain the scaled images of the sample 1 as the output of the X-ray image pickup device 4. In addition, a sample holding/moving means 3 to hold the sample 1 is controlled by the controller 7 to move the sample 1 according to an amount corresponding to the deflection of electrons 45 in the directions B which are the moving directions of X rays 50 at the time when the electrons 45 are deflected in the first directions A by the sample holding/moving means 3 to enable the same position of the sample 1 to be irradiated with the X-rays 50, and then the scaled images including the same position of the sample 1 are obtained as the output of the X-ray image pickup device 4.



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